



Testing Sequence Dependent Defects

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Condition: New. Publisher/Verlag: LAP Lambert Academic Publishing | New Methods of Applying Two-pattern Tests and Testing Sequence Dependent Defects | With new technologies that continue to shrink the feature size of integrated circuits into deep sub-micron domain, there is an increasingly higher incidence of sequence dependent defects during manufacturing. Two-pattern tests are therefore being used in manufacturing testing to supplement the traditional method of single pattern tests based on the stuck-at fault model. In this work we present methods of generating and applying two-pattern test sets to enable high quality and cost effective testing of sequence dependent defects such as transition delay faults, transistor stuck-open faults etc. | Format: Paperback | Language/Sprache: english | 116 pp.



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